

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components, Assemblies, Related Materials and Processes

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Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-01

CB Certificate No.: 20001846 ITL

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Appendix-1 (20001846 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
X-Ray imaging	T-EFA-3
Optical Microscope (OM)	T-OMI-3
3D Optical Microscope (3D OM)	T-LAB-3

michael Chou Technical Reviewer of DQS: Date: 8/15/2023

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